

Notice of References Cited	Application/Control No. 10/749,564		Applicant(s)/Patent Under Reexamination CHUANG ET AL.	
	Examiner BRIAN P. YENKE		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0041918	03-2004	Chan et al.	348/222.1
*	B	US-6,674,443	01-2004	Chowdhuri et al.	345/557
*	C	US-6,177,922	01-2001	Schiefer et al.	345/698
*	D	US-5,814,439	09-1998	Ohshima et al.	430/567
*	E	US-7,081,902	07-2006	Crow et al.	345/611
*	F	US-6,661,427	12-2003	MacInnis et al.	345/660
*	G	US-6,650,792	11-2003	Aida et al.	382/298
*	H	US-6,563,511	05-2003	Yeh et al.	345/611
*	I	US-6,157,396	12-2000	Margulis et al.	345/506
*	J	US-6,456,340	05-2002	Margulis, Neal	348/745
*	K	US-2002/0063807	05-2002	Margulis, Neal	348/745
*	L	US-6,680,752	01-2004	Callway et al.	348/448
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.